34.4.2 Core engine / control logic

This block contains RNGA's control logic as well as its core engine used to generate random data.

34.4.2.1 Control logic

The control logic contains the address decoder, all addressable registers, and control state machines for RNGA. This block is responsible for communication with both the peripheral interface and the Output (OR) register interface. The block also controls the core engine to generate random data. The general functionality of the block is as follows:

After reset, RNGA operates in Normal mode as follows:

- 1. The core engine generates entropy and stores it in the shift registers.
- 2. After you enable random-data generation by loading CR[GO], every 256 clock cycles the core engine generates a new random-data word. If SR[OREG_LVL] = 0, then the control block loads the new random data into OR and set SR[OREG_LVL] = 1; else the new data is discarded.

34.4.2.2 Core engine

The core engine block contains the logic used to generate random data. The logic within the core engine contains the internal shift registers as well as the logic used to generate the two oscillator-based clocks. The control logic determines how the shift registers are configured as well as when the oscillator clocks are turned on.

34.5 Initialization/application information

The intended general operation of RNGA is as follows:

- 1. Reset/initialize.
- 2. Write 1 to CR[INTM], CR[HA], and CR[GO].
- 3. Poll SR[OREG_LVL] until it is not 0.
- 4. When SR[OREG_LVL] is not 0, read the available random data from OR[RANDOUT].
- 5. Repeat steps 3 and 4 as needed.

Initialization/application information

For application information, see Overview.

Chapter 35 Analog-to-Digital Converter (ADC)

35.1 Introduction

NOTE

For the chip-specific implementation details of this module's instances, see the chip configuration information.

The 16-bit analog-to-digital converter (ADC) is a successive approximation ADC designed for operation within an integrated microcontroller system-on-chip.

NOTE

For the chip specific modes of operation, see the power management information of the device.

35.1.1 Features

Following are the features of the ADC module.

- Linear successive approximation algorithm with up to 16-bit resolution
- Up to four pairs of differential and 24 single-ended external analog inputs
- Output modes:
 - differential 16-bit, 13-bit, 11-bit, and 9-bit modes
 - single-ended 16-bit, 12-bit, 10-bit, and 8-bit modes
- Output format in 2's complement 16-bit sign extended for differential modes
- Output in right-justified unsigned format for single-ended
- Single or continuous conversion, that is, automatic return to idle after single conversion

Introduction

- Configurable sample time and conversion speed/power
- Conversion complete/hardware average complete flag and interrupt
- Input clock selectable from up to four sources
- Operation in low-power modes for lower noise
- Asynchronous clock source for lower noise operation with option to output the clock
- Selectable hardware conversion trigger with hardware channel select
- Automatic compare with interrupt for less-than, greater-than or equal-to, within range, or out-of-range, programmable value
- Temperature sensor
- Hardware average function
- Selectable voltage reference: external or alternate
- Self-Calibration mode

35.1.2 Block diagram

The following figure is the ADC module block diagram.

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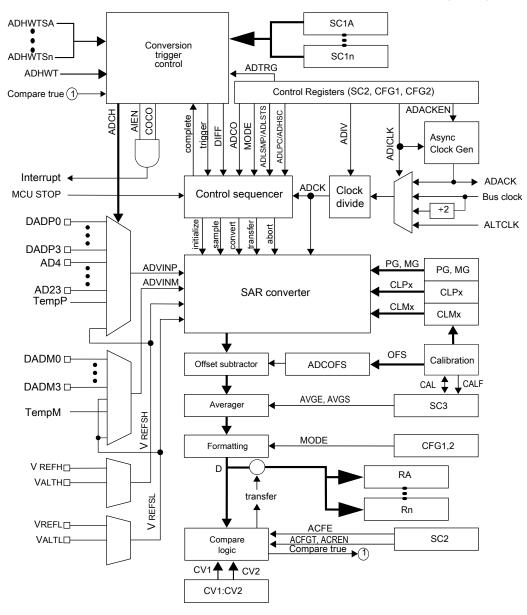


Figure 35-1. ADC block diagram

35.2 ADC signal descriptions

The ADC module supports up to 4 pairs of differential inputs and up to 24 single-ended inputs.

Each differential pair requires two inputs, DADPx and DADMx. The ADC also requires four supply/reference/ground connections.

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NOTE

For the number of channels supported on this device as well as information regarding other chip-specific inputs into the ADC block, see the chip-specific ADC configuration information.

Table 35-1. ADC signal descriptions

Signal	Description	I/O
DADP3-DADP0	Differential Analog Channel Inputs	I
DADM3-DADM0	Differential Analog Channel Inputs	I
AD <i>n</i>	Single-Ended Analog Channel Inputs	I
V _{REFSH}	Voltage Reference Select High	I
V _{REFSL}	Voltage Reference Select Low	I
V_{DDA}	Analog Power Supply	I
V _{SSA}	Analog Ground	I

35.2.1 Analog Power (V_{DDA})

The ADC analog portion uses V_{DDA} as its power connection. In some packages, V_{DDA} is connected internally to V_{DD} . If externally available, connect the V_{DDA} pin to the same voltage potential as V_{DD} . External filtering may be necessary to ensure clean V_{DDA} for good results.

35.2.2 Analog Ground (V_{SSA})

The ADC analog portion uses V_{SSA} as its ground connection. In some packages, V_{SSA} is connected internally to V_{SS} . If externally available, connect the V_{SSA} pin to the same voltage potential as V_{SS} .

35.2.3 Voltage Reference Select

V_{REFSH} and V_{REFSL} are the high and low reference voltages for the ADC module.

The ADC can be configured to accept one of two voltage reference pairs for V_{REFSH} and V_{REFSL} . Each pair contains a positive reference that must be between the minimum Ref Voltage High and V_{DDA} , and a ground reference that must be at the same potential as V_{SSA} . The two pairs are external (V_{REFH} and V_{REFL}) and alternate (V_{ALTH} and V_{ALTL}). These voltage references are selected using SC2[REFSEL]. The alternate V_{ALTH} and

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V_{ALTL} voltage reference pair may select additional external pins or internal sources depending on MCU configuration. See the chip configuration information on the Voltage References specific to this MCU.

In some packages, V_{REFH} is connected in the package to V_{DDA} and V_{REFL} to V_{SSA} . If externally available, the positive reference(s) may be connected to the same potential as V_{DDA} or may be driven by an external source to a level between the minimum Ref Voltage High and the V_{DDA} potential. V_{REFH} must never exceed V_{DDA} . Connect the ground references to the same voltage potential as V_{SSA} .

35.2.4 Analog Channel Inputs (ADx)

The ADC module supports up to 24 single-ended analog inputs. A single-ended input is selected for conversion through the SC1[ADCH] channel select bits when SC1n[DIFF] is low.

35.2.5 Differential Analog Channel Inputs (DADx)

The ADC module supports up to four differential analog channel inputs. Each differential analog input is a pair of external pins, DADPx and DADMx, referenced to each other to provide the most accurate analog to digital readings. A differential input is selected for conversion through SC1[ADCH] when SC1n[DIFF] is high. All DADPx inputs may be used as single-ended inputs if SC1n[DIFF] is low. In certain MCU configurations, some DADMx inputs may also be used as single-ended inputs if SC1n[DIFF] is low. For ADC connections specific to this device, see the chip-specific ADC information.

35.3 Memory map and register definitions

This section describes the ADC registers.

ADC memory map

Absolute address (hex)	Register name	Width (in bits)	Access	Reset value	Section/ page
4003_B000	ADC Status and Control Registers 1 (ADC0_SC1A)	32	R/W	0000_001Fh	35.3.1/853
4003_B004	ADC Status and Control Registers 1 (ADC0_SC1B)	32	R/W	0000_001Fh	35.3.1/853
4003_B008	ADC Configuration Register 1 (ADC0_CFG1)	32	R/W	0000_0000h	35.3.2/857
4003_B00C	ADC Configuration Register 2 (ADC0_CFG2)	32	R/W	0000_0000h	35.3.3/858
4003_B010	ADC Data Result Register (ADC0_RA)	32	R	0000_0000h	35.3.4/859

Table continues on the next page...

Memory map and register definitions

ADC memory map (continued)

Absolute address (hex)	Register name	Width (in bits)	Access	Reset value	Section/ page
4003_B014	ADC Data Result Register (ADC0_RB)	32	R	0000_0000h	35.3.4/859
4003_B018	Compare Value Registers (ADC0_CV1)	32	R/W	0000_0000h	35.3.5/861
4003_B01C	Compare Value Registers (ADC0_CV2)	32	R/W	0000_0000h	35.3.5/861
4003_B020	Status and Control Register 2 (ADC0_SC2)	32	R/W	0000_0000h	35.3.6/862
4003_B024	Status and Control Register 3 (ADC0_SC3)	32	R/W	0000_0000h	35.3.7/864
4003_B028	ADC Offset Correction Register (ADC0_OFS)	32	R/W	0000_0004h	35.3.8/865
4003_B02C	ADC Plus-Side Gain Register (ADC0_PG)	32	R/W	0000_8200h	35.3.9/866
4003_B030	ADC Minus-Side Gain Register (ADC0_MG)	32	R/W	0000_8200h	35.3.10/ 866
4003_B034	ADC Plus-Side General Calibration Value Register (ADC0_CLPD)	32	R/W	0000_000Ah	35.3.11/ 867
4003_B038	ADC Plus-Side General Calibration Value Register (ADC0_CLPS)	32	R/W	0000_0020h	35.3.12/ 868
4003_B03C	ADC Plus-Side General Calibration Value Register (ADC0_CLP4)	32	R/W	0000_0200h	35.3.13/ 868
4003_B040	ADC Plus-Side General Calibration Value Register (ADC0_CLP3)	32	R/W	0000_0100h	35.3.14/ 869
4003_B044	ADC Plus-Side General Calibration Value Register (ADC0_CLP2)	32	R/W	0000_0080h	35.3.15/ 869
4003_B048	ADC Plus-Side General Calibration Value Register (ADC0_CLP1)	32	R/W	0000_0040h	35.3.16/ 870
4003_B04C	ADC Plus-Side General Calibration Value Register (ADC0_CLP0)	32	R/W	0000_0020h	35.3.17/ 870
4003_B054	ADC Minus-Side General Calibration Value Register (ADC0_CLMD)	32	R/W	0000_000Ah	35.3.18/ 871
4003_B058	ADC Minus-Side General Calibration Value Register (ADC0_CLMS)	32	R/W	0000_0020h	35.3.19/ 871
4003_B05C	ADC Minus-Side General Calibration Value Register (ADC0_CLM4)	32	R/W	0000_0200h	35.3.20/ 872
4003_B060	ADC Minus-Side General Calibration Value Register (ADC0_CLM3)	32	R/W	0000_0100h	35.3.21/ 872
4003_B064	ADC Minus-Side General Calibration Value Register (ADC0_CLM2)	32	R/W	0000_0080h	35.3.22/ 873
4003_B068	ADC Minus-Side General Calibration Value Register (ADC0_CLM1)	32	R/W	0000_0040h	35.3.23/ 873
4003_B06C	ADC Minus-Side General Calibration Value Register (ADC0_CLM0)	32	R/W	0000_0020h	35.3.24/ 874
400B_B000	ADC Status and Control Registers 1 (ADC1_SC1A)	32	R/W	0000_001Fh	35.3.1/853
400B_B004	ADC Status and Control Registers 1 (ADC1_SC1B)	32	R/W	0000_001Fh	35.3.1/853
400B_B008	ADC Configuration Register 1 (ADC1_CFG1)	32	R/W	0000_0000h	35.3.2/857
400B_B00C	ADC Configuration Register 2 (ADC1_CFG2)	32	R/W	0000_0000h	35.3.3/858
400B_B010	ADC Data Result Register (ADC1_RA)	32	R	0000_0000h	35.3.4/859

Table continues on the next page...

ADC memory map (continued)

Absolute address (hex)	Register name	Width (in bits)	Access	Reset value	Section/ page
400B_B014	ADC Data Result Register (ADC1_RB)	32	R	0000_0000h	35.3.4/859
400B_B018	Compare Value Registers (ADC1_CV1)	32	R/W	0000_0000h	35.3.5/861
400B_B01C	Compare Value Registers (ADC1_CV2)	32	R/W	0000_0000h	35.3.5/861
400B_B020	Status and Control Register 2 (ADC1_SC2)	32	R/W	0000_0000h	35.3.6/862
400B_B024	Status and Control Register 3 (ADC1_SC3)	32	R/W	0000_0000h	35.3.7/864
400B_B028	ADC Offset Correction Register (ADC1_OFS)	32	R/W	0000_0004h	35.3.8/865
400B_B02C	ADC Plus-Side Gain Register (ADC1_PG)	32	R/W	0000_8200h	35.3.9/866
400B_B030	ADC Minus-Side Gain Register (ADC1_MG)	32	R/W	0000_8200h	35.3.10/ 866
400B_B034	ADC Plus-Side General Calibration Value Register (ADC1_CLPD)	32	R/W	0000_000Ah	35.3.11/ 867
400B_B038	ADC Plus-Side General Calibration Value Register (ADC1_CLPS)	32	R/W	0000_0020h	35.3.12/ 868
400B_B03C	ADC Plus-Side General Calibration Value Register (ADC1_CLP4)	32	R/W	0000_0200h	35.3.13/ 868
400B_B040	ADC Plus-Side General Calibration Value Register (ADC1_CLP3)	32	R/W	0000_0100h	35.3.14/ 869
400B_B044	ADC Plus-Side General Calibration Value Register (ADC1_CLP2)	32	R/W	0000_0080h	35.3.15/ 869
400B_B048	ADC Plus-Side General Calibration Value Register (ADC1_CLP1)	32	R/W	0000_0040h	35.3.16/ 870
400B_B04C	ADC Plus-Side General Calibration Value Register (ADC1_CLP0)	32	R/W	0000_0020h	35.3.17/ 870
400B_B054	ADC Minus-Side General Calibration Value Register (ADC1_CLMD)	32	R/W	0000_000Ah	35.3.18/ 871
400B_B058	ADC Minus-Side General Calibration Value Register (ADC1_CLMS)	32	R/W	0000_0020h	35.3.19/ 871
400B_B05C	ADC Minus-Side General Calibration Value Register (ADC1_CLM4)	32	R/W	0000_0200h	35.3.20/ 872
400B_B060	ADC Minus-Side General Calibration Value Register (ADC1_CLM3)	32	R/W	0000_0100h	35.3.21/ 872
400B_B064	ADC Minus-Side General Calibration Value Register (ADC1_CLM2)	32	R/W	0000_0080h	35.3.22/ 873
400B_B068	ADC Minus-Side General Calibration Value Register (ADC1_CLM1)	32	R/W	0000_0040h	35.3.23/ 873
400B_B06C	ADC Minus-Side General Calibration Value Register (ADC1_CLM0)	32	R/W	0000_0020h	35.3.24/ 874

35.3.1 ADC Status and Control Registers 1 (ADCx_SC1n)

SC1A is used for both software and hardware trigger modes of operation.

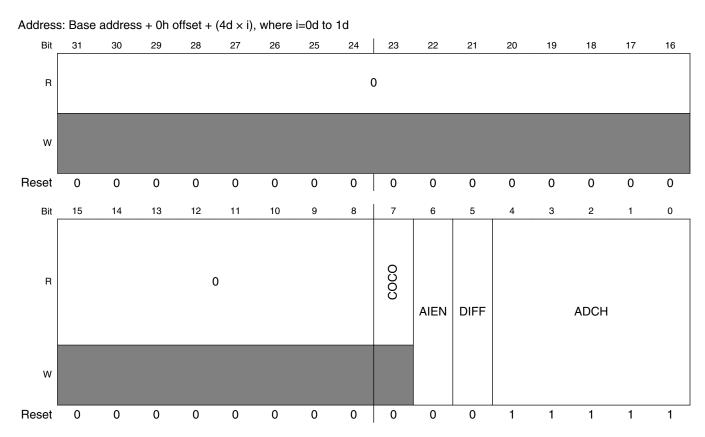
Memory map and register definitions

To allow sequential conversions of the ADC to be triggered by internal peripherals, the ADC can have more than one status and control register: one for each conversion. The SC1B–SC1n registers indicate potentially multiple SC1 registers for use only in hardware trigger mode. See the chip configuration information about the number of SC1n registers specific to this device. The SC1n registers have identical fields, and are used in a "ping-pong" approach to control ADC operation.

At any one point in time, only one of the SC1n registers is actively controlling ADC conversions. Updating SC1A while SC1n is actively controlling a conversion is allowed, and vice-versa for any of the SC1n registers specific to this MCU.

Writing SC1A while SC1A is actively controlling a conversion aborts the current conversion. In Software Trigger mode, when SC2[ADTRG]=0, writes to SC1A subsequently initiate a new conversion, if SC1[ADCH] contains a value other than all 1s (module disabled).

Writing any of the SC1n registers while that specific SC1n register is actively controlling a conversion aborts the current conversion. None of the SC1B-SC1n registers are used for software trigger operation and therefore writes to the SC1B-SC1n registers do not initiate a new conversion.



ADCx_SC1n field descriptions

Field	Description
31–8 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
7 COCO	Conversion Complete Flag This is a read-only field that is set each time a conversion is completed when the compare function is
	disabled, or SC2[ACFE]=0 and the hardware average function is disabled, or SC3[AVGE]=0. When the compare function is enabled, or SC2[ACFE]=1, COCO is set upon completion of a conversion only if the compare result is true. When the hardware average function is enabled, or SC3[AVGE]=1, COCO is set upon completion of the selected number of conversions (determined by AVGS). COCO in SC1A is also set at the completion of a calibration sequence. COCO is cleared when the respective SC1n register is written or when the respective Rn register is read.
	0 Conversion is not completed.
	1 Conversion is completed.
6	Interrupt Enable
AIEN	Enables conversion complete interrupts. When COCO becomes set while the respective AIEN is high, an interrupt is asserted.
	0 Conversion complete interrupt is disabled.
	1 Conversion complete interrupt is enabled.
5 DIFF	Differential Mode Enable
	Configures the ADC to operate in differential mode. When enabled, this mode automatically selects from the differential channels, and changes the conversion algorithm and the number of cycles to complete a conversion.
	0 Single-ended conversions and input channels are selected.
	1 Differential conversions and input channels are selected.
ADCH	Input channel select
	Selects one of the input channels. The input channel decode depends on the value of DIFF. DAD0-DAD3 are associated with the input pin pairs DADPx and DADMx.
	NOTE: Some of the input channel options in the bitfield-setting descriptions might not be available for your device. For the actual ADC channel assignments for your device, see the Chip Configuration details.
	The successive approximation converter subsystem is turned off when the channel select bits are all set, that is, ADCH = 11111. This feature allows explicit disabling of the ADC and isolation of the input channel from all sources. Terminating continuous conversions this way prevents an additional single conversion from being performed. It is not necessary to set ADCH to all 1s to place the ADC in a low-power state when continuous conversions are not enabled because the module automatically enters a low-power state when a conversion completes.
	00000 When DIFF=0, DADP0 is selected as input; when DIFF=1, DAD0 is selected as input. 00001 When DIFF=0, DADP1 is selected as input; when DIFF=1, DAD1 is selected as input. 00010 When DIFF=0, DADP2 is selected as input; when DIFF=1, DAD2 is selected as input. 00011 When DIFF=0, DADP3 is selected as input; when DIFF=1, DAD3 is selected as input. 00100 When DIFF=0, AD4 is selected as input; when DIFF=1, it is reserved.
	00101 When DIFF=0, AD5 is selected as input; when DIFF=1, it is reserved.
	00110 When DIFF=0, AD6 is selected as input; when DIFF=1, it is reserved.
	00111 When DIFF=0, AD7 is selected as input; when DIFF=1, it is reserved.

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Memory map and register definitions

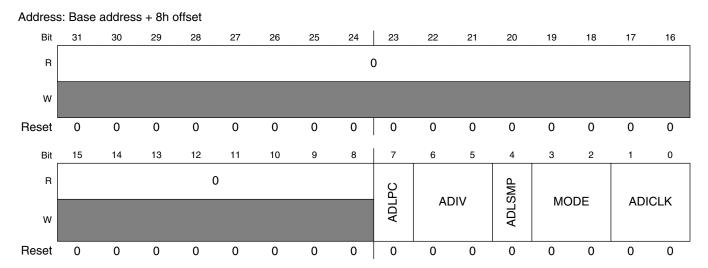
ADCx_SC1n field descriptions (continued)

Field		Description
	01000	When DIFF=0, AD8 is selected as input; when DIFF=1, it is reserved.
	01001	When DIFF=0, AD9 is selected as input; when DIFF=1, it is reserved.
	01010	When DIFF=0, AD10 is selected as input; when DIFF=1, it is reserved.
	01011	When DIFF=0, AD11 is selected as input; when DIFF=1, it is reserved.
	01100	When DIFF=0, AD12 is selected as input; when DIFF=1, it is reserved.
	01101	When DIFF=0, AD13 is selected as input; when DIFF=1, it is reserved.
	01110	When DIFF=0, AD14 is selected as input; when DIFF=1, it is reserved.
	01111	When DIFF=0, AD15 is selected as input; when DIFF=1, it is reserved.
	10000	When DIFF=0, AD16 is selected as input; when DIFF=1, it is reserved.
	10001	When DIFF=0, AD17 is selected as input; when DIFF=1, it is reserved.
	10010	When DIFF=0, AD18 is selected as input; when DIFF=1, it is reserved.
	10011	When DIFF=0, AD19 is selected as input; when DIFF=1, it is reserved.
	10100	When DIFF=0, AD20 is selected as input; when DIFF=1, it is reserved.
	10101	When DIFF=0, AD21 is selected as input; when DIFF=1, it is reserved.
	10110	When DIFF=0, AD22 is selected as input; when DIFF=1, it is reserved.
	10111	When DIFF=0, AD23 is selected as input; when DIFF=1, it is reserved.
	11000	Reserved.
	11001	Reserved.
	11010	When DIFF=0, Temp Sensor (single-ended) is selected as input; when DIFF=1, Temp Sensor (differential) is selected as input.
	11011	When DIFF=0,Bandgap (single-ended) is selected as input; when DIFF=1, Bandgap (differential) is selected as input.
	11100	Reserved.
	11101	When DIFF=0,V _{REFSH} is selected as input; when DIFF=1, -V _{REFSH} (differential) is selected as input. Voltage reference selected is determined by SC2[REFSEL].
	11110	When DIFF=0,V _{REFSL} is selected as input; when DIFF=1, it is reserved. Voltage reference selected is determined by SC2[REFSEL].
	11111	Module is disabled.

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35.3.2 ADC Configuration Register 1 (ADCx_CFG1)

The configuration Register 1 (CFG1) selects the mode of operation, clock source, clock divide, and configuration for low power or long sample time.



ADCx_CFG1 field descriptions

Field	Description
31–8	This field is reserved.
Reserved	This read-only field is reserved and always has the value 0.
7	Low-Power Configuration
ADLPC	Controls the power configuration of the successive approximation converter. This optimizes power consumption when higher sample rates are not required.
	0 Normal power configuration.
	1 Low-power configuration. The power is reduced at the expense of maximum clock speed.
6–5 ADIV	Clock Divide Select
	Selects the divide ratio used by the ADC to generate the internal clock ADCK.
	00 The divide ratio is 1 and the clock rate is input clock.
	01 The divide ratio is 2 and the clock rate is (input clock)/2.
	10 The divide ratio is 4 and the clock rate is (input clock)/4.
	11 The divide ratio is 8 and the clock rate is (input clock)/8.
4 ADLSMP	Sample Time Configuration
	Selects between different sample times based on the conversion mode selected. This field adjusts the sample period to allow higher impedance inputs to be accurately sampled or to maximize conversion speed for lower impedance inputs. Longer sample times can also be used to lower overall power consumption if continuous conversions are enabled and high conversion rates are not required. When ADLSMP=1, the long sample time select bits, (ADLSTS[1:0]), can select the extent of the long sample time.

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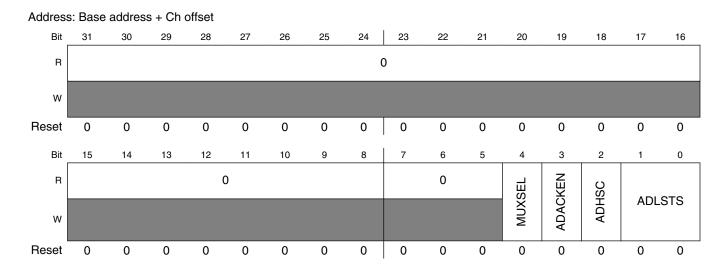
Memory map and register definitions

ADCx_CFG1 field descriptions (continued)

Field	Description
	0 Short sample time.
	1 Long sample time.
3–2 MODE	Conversion mode selection
	Selects the ADC resolution mode.
	00 When DIFF=0:It is single-ended 8-bit conversion; when DIFF=1, it is differential 9-bit conversion with 2's complement output.
	01 When DIFF=0:It is single-ended 12-bit conversion; when DIFF=1, it is differential 13-bit conversion with 2's complement output.
	10 When DIFF=0:It is single-ended 10-bit conversion.; when DIFF=1, it is differential 11-bit conversion with 2's complement output
	11 When DIFF=0:It is single-ended 16-bit conversion; when DIFF=1, it is differential 16-bit conversion with 2's complement output
ADICLK	Input Clock Select
	Selects the input clock source to generate the internal clock, ADCK. Note that when the ADACK clock source is selected, it is not required to be active prior to conversion start. When it is selected and it is not active prior to a conversion start, when CFG2[ADACKEN]=0, the asynchronous clock is activated at the start of a conversion and deactivated when conversions are terminated. In this case, there is an associated clock startup delay each time the clock source is re-activated.
	00 Bus clock
	01 Bus clock divided by 2(BUSCLK/2)
	10 Alternate clock (ALTCLK)
	11 Asynchronous clock (ADACK)

35.3.3 ADC Configuration Register 2 (ADCx_CFG2)

Configuration Register 2 (CFG2) selects the special high-speed configuration for very high speed conversions and selects the long sample time duration during long sample mode.



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ADCx_CFG2 field descriptions

Field	Description
31–8 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
7–5 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
4 MUXSEL	ADC Mux Select Changes the ADC mux setting to select between alternate sets of ADC channels.
	0 ADxxa channels are selected.
	1 ADxxb channels are selected.
3 ADACKEN	Asynchronous Clock Output Enable
	Enables the asynchronous clock source and the clock source output regardless of the conversion and status of CFG1[ADICLK]. Based on MCU configuration, the asynchronous clock may be used by other modules. See chip configuration information. Setting this field allows the clock to be used even while the ADC is idle or operating from a different clock source. Also, latency of initiating a single or first-continuous conversion with the asynchronous clock selected is reduced because the ADACK clock is already operational.
	O Asynchronous clock output disabled; Asynchronous clock is enabled only if selected by ADICLK and a conversion is active.
	1 Asynchronous clock and clock output is enabled regardless of the state of the ADC.
2 ADHSC	High-Speed Configuration
	Configures the ADC for very high-speed operation. The conversion sequence is altered with 2 ADCK cycles added to the conversion time to allow higher speed conversion clocks.
	0 Normal conversion sequence selected.
	1 High-speed conversion sequence selected with 2 additional ADCK cycles to total conversion time.
ADLSTS	Long Sample Time Select
	Selects between the extended sample times when long sample time is selected, that is, when CFG1[ADLSMP]=1. This allows higher impedance inputs to be accurately sampled or to maximize conversion speed for lower impedance inputs. Longer sample times can also be used to lower overall power consumption when continuous conversions are enabled if high conversion rates are not required.
	00 Default longest sample time; 20 extra ADCK cycles; 24 ADCK cycles total.
	01 12 extra ADCK cycles; 16 ADCK cycles total sample time.
	10 6 extra ADCK cycles; 10 ADCK cycles total sample time.
	11 2 extra ADCK cycles; 6 ADCK cycles total sample time.

35.3.4 ADC Data Result Register (ADCx_Rn)

The data result registers (Rn) contain the result of an ADC conversion of the channel selected by the corresponding status and channel control register (SC1A:SC1n). For every status and channel control register, there is a corresponding data result register.

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Memory map and register definitions

Unused bits in R n are cleared in unsigned right-aligned modes and carry the sign bit (MSB) in sign-extended 2's complement modes. For example, when configured for 10-bit single-ended mode, D[15:10] are cleared. When configured for 11-bit differential mode, D[15:10] carry the sign bit, that is, bit 10 extended through bit 15.

The following table describes the behavior of the data result registers in the different modes of operation.

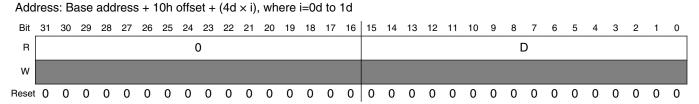
D13 D12 D11 D10 D9 D8 D4 D1 D0 D15 D14 **D7** D6 D5 D3 D2 Conversion **Format** mode D 16-bit differential S D D D D D D D D D D D D D D Signed 2's complement 16-bit single-D D D D D D D D D D D D D D D Unsigned right ended justified 13-bit differential S S S S D D D D D D D D D D D D Sign-extended 2's complement 12-bit single-0 0 0 D D D D D D D D D D Unsigned right-D ended iustified S S S S D D D 11-bit differential S S D D D D D D D Sian-extended 2's complement 10-bit single-0 0 0 0 0 0 D D D D D Unsigned right-D D D D D ended iustified 9-bit differential S S S S S S S S D D D D D D D D Sign-extended 2's complement 0 0 0 0 0 D D D 8-bit single-0 0 0 D D D D D Unsigned rightended justified

Table 35-2. Data result register description

NOTE

S: Sign bit or sign bit extension;

D: Data, which is 2's complement data if indicated



ADCx Rn field descriptions

Field	Description
	This field is reserved. This read-only field is reserved and always has the value 0.
D	Data result

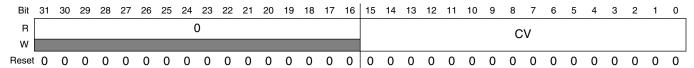
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35.3.5 Compare Value Registers (ADCx_CVn)

The Compare Value Registers (CV1 and CV2) contain a compare value used to compare the conversion result when the compare function is enabled, that is, SC2[ACFE]=1. This register is formatted in the same way as the Rn registers in different modes of operation for both bit position definition and value format using unsigned or sign-extended 2's complement. Therefore, the compare function uses only the CVn fields that are related to the ADC mode of operation.

The compare value 2 register (CV2) is used only when the compare range function is enabled, that is, SC2[ACREN]=1.



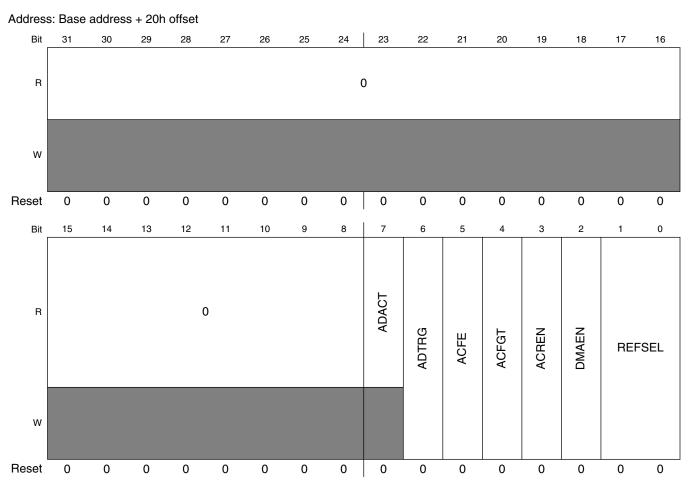


ADCx_CVn field descriptions

Field	Description
31–16 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
CV	Compare Value.

35.3.6 Status and Control Register 2 (ADCx_SC2)

The status and control register 2 (SC2) contains the conversion active, hardware/software trigger select, compare function, and voltage reference select of the ADC module.



ADCx_SC2 field descriptions

Field	Description
31–8 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
7 ADACT	Conversion Active Indicates that a conversion or hardware averaging is in progress. ADACT is set when a conversion is initiated and cleared when a conversion is completed or aborted. O Conversion not in progress. Conversion in progress.
6 ADTRG	Conversion Trigger Select Selects the type of trigger used for initiating a conversion. Two types of trigger are selectable:

Table continues on the next page...

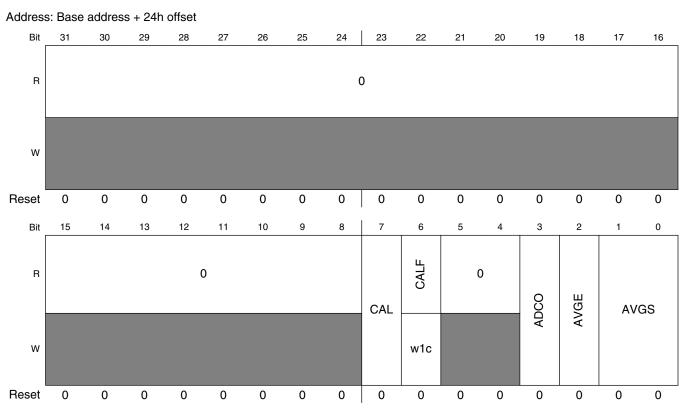
ADCx_SC2 field descriptions (continued)

Field	Description
	Software trigger: When software trigger is selected, a conversion is initiated following a write to SC1A.
	 Hardware trigger: When hardware trigger is selected, a conversion is initiated following the assertion of the ADHWT input after a pulse of the ADHWTSn input.
	0 Software trigger selected.
	1 Hardware trigger selected.
5 ACFE	Compare Function Enable Enables the compare function.
	Enables the compare function.
	0 Compare function disabled.
	1 Compare function enabled.
4 ACFGT	Compare Function Greater Than Enable
	Configures the compare function to check the conversion result relative to the CV1 and CV2 based upon the value of ACREN. ACFE must be set for ACFGT to have any effect.
	O Configures less than threshold, outside range not inclusive and inside range not inclusive; functionality based on the values placed in CV1 and CV2.
	1 Configures greater than or equal to threshold, outside and inside ranges inclusive; functionality based on the values placed in CV1 and CV2.
3 ACREN	Compare Function Range Enable
	Configures the compare function to check if the conversion result of the input being monitored is either between or outside the range formed by CV1 and CV2 determined by the value of ACFGT. ACFE must be set for ACFGT to have any effect.
	0 Range function disabled. Only CV1 is compared.
	1 Range function enabled. Both CV1 and CV2 are compared.
2 DMAEN	DMA Enable
DWINEIN	0 DMA is disabled.
	1 DMA is enabled and will assert the ADC DMA request during an ADC conversion complete event noted when any of the SC1n[COCO] flags is asserted.
REFSEL	Voltage Reference Selection
	Selects the voltage reference source used for conversions.
	00 Default voltage reference pin pair, that is, external pins V _{REFH} and V _{REFL}
	O1 Alternate reference pair, that is, V _{ALTH} and V _{ALTL} . This pair may be additional external pins or internal sources depending on the MCU configuration. See the chip configuration information for details specific to this MCU
	10 Reserved
	11 Reserved

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35.3.7 Status and Control Register 3 (ADCx_SC3)

The Status and Control Register 3 (SC3) controls the calibration, continuous convert, and hardware averaging functions of the ADC module.



ADCx_SC3 field descriptions

Field	Description
31–8	This field is reserved.
Reserved	This read-only field is reserved and always has the value 0.
7	Calibration
CAL	
	Begins the calibration sequence when set. This field stays set while the calibration is in progress and is cleared when the calibration sequence is completed. CALF must be checked to determine the result of the calibration sequence. Once started, the calibration routine cannot be interrupted by writes to the ADC registers or the results will be invalid and CALF will set. Setting CAL will abort any current conversion.
6	Calibration Failed Flag
CALF	Displays the result of the calibration sequence. The calibration sequence will fail if SC2[ADTRG] = 1, any ADC register is written, or any stop mode is entered before the calibration sequence completes. Writing 1 to CALF clears it.
	0 Calibration completed normally.
	1 Calibration failed. ADC accuracy specifications are not guaranteed.
5–4	This field is reserved.
Reserved	This read-only field is reserved and always has the value 0.

Table continues on the next page...

ADCx_SC3 field descriptions (continued)

Field	Description
3 ADCO	Continuous Conversion Enable
7.200	Enables continuous conversions.
	One conversion or one set of conversions if the hardware average function is enabled, that is, AVGE=1, after initiating a conversion.
	1 Continuous conversions or sets of conversions if the hardware average function is enabled, that is, AVGE=1, after initiating a conversion.
2 AVGE	Hardware Average Enable
71702	Enables the hardware average function of the ADC.
	0 Hardware average function disabled.
	1 Hardware average function enabled.
AVGS	Hardware Average Select
	Determines how many ADC conversions will be averaged to create the ADC average result.
	00 4 samples averaged.
	01 8 samples averaged.
	10 16 samples averaged.
	11 32 samples averaged.

35.3.8 ADC Offset Correction Register (ADCx_OFS)

The ADC Offset Correction Register (OFS) contains the user-selected or calibration-generated offset error correction value. This register is a 2's complement, left-justified, 16-bit value . The value in OFS is subtracted from the conversion and the result is transferred into the result registers, Rn. If the result is greater than the maximum or less than the minimum result value, it is forced to the appropriate limit for the current mode of operation.

For more information regarding the calibration procedure, please refer to the Calibration function section.

Address: Base address + 28h offset



ADCx OFS field descriptions

Field	Description
31–16	This field is reserved.
Reserved	This read-only field is reserved and always has the value 0.

Table continues on the next page...

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ADCx_OFS field descriptions (continued)

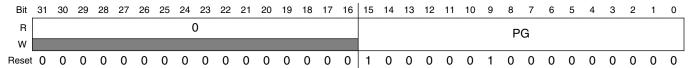
Field	Description
OFS	Offset Error Correction Value

35.3.9 ADC Plus-Side Gain Register (ADCx_PG)

The Plus-Side Gain Register (PG) contains the gain error correction for the plus-side input in differential mode or the overall conversion in single-ended mode. PG, a 16-bit real number in binary format, is the gain adjustment factor, with the radix point fixed between PG[15] and PG[14]. This register must be written by the user with the value described in the calibration procedure. Otherwise, the gain error specifications may not be met.

For more information regarding the calibration procedure, please refer to the Calibration function section.





ADCx_PG field descriptions

Field	Description
	This field is reserved. This read-only field is reserved and always has the value 0.
PG	Plus-Side Gain

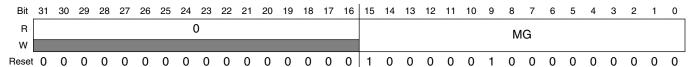
35.3.10 ADC Minus-Side Gain Register (ADCx_MG)

The Minus-Side Gain Register (MG) contains the gain error correction for the minus-side input in differential mode. This register is ignored in single-ended mode. MG, a 16-bit real number in binary format, is the gain adjustment factor, with the radix point fixed between MG[15] and MG[14]. This register must be written by the user with the value described in the calibration procedure. Otherwise, the gain error specifications may not be met.

For more information regarding the calibration procedure, please refer to the Calibration function section.

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Address: Base address + 30h offset



ADCx_MG field descriptions

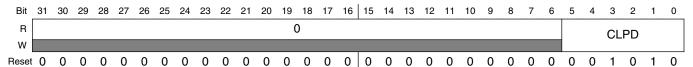
Field	Description
31–16 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
MG	Minus-Side Gain

35.3.11 ADC Plus-Side General Calibration Value Register (ADCx_CLPD)

The Plus-Side General Calibration Value Registers (CLPx) contain calibration information that is generated by the calibration function. These registers contain seven calibration values of varying widths: CLP0[5:0], CLP1[6:0], CLP2[7:0], CLP3[8:0], CLP4[9:0], CLPS[5:0], and CLPD[5:0]. CLPx are automatically set when the self-calibration sequence is done, that is, CAL is cleared. If these registers are written by the user after calibration, the linearity error specifications may not be met.

For more information regarding the calibration procedure, please refer to the Calibration function section.

Address: Base address + 34h offset



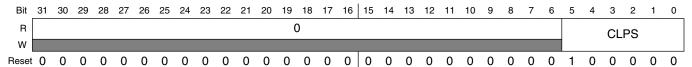
ADCx_CLPD field descriptions

Field	Description
31–6 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
CLPD	Calibration Value
	Calibration Value

35.3.12 ADC Plus-Side General Calibration Value Register (ADCx_CLPS)

For more information, see CLPD register description.

Address: Base address + 38h offset



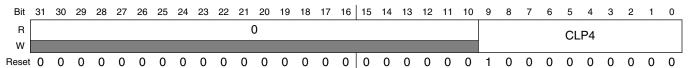
ADCx CLPS field descriptions

Field	Description
31–6 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
CLPS	Calibration Value
	Calibration Value

35.3.13 ADC Plus-Side General Calibration Value Register (ADCx_CLP4)

For more information, see CLPD register description.

Address: Base address + 3Ch offset



ADCx_CLP4 field descriptions

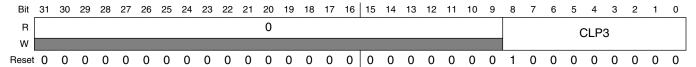
Field	Description
31–10 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
CLP4	Calibration Value
	Calibration Value

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35.3.14 ADC Plus-Side General Calibration Value Register (ADCx_CLP3)

For more information, see CLPD register description.

Address: Base address + 40h offset



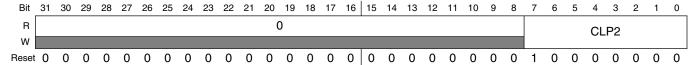
ADCx_CLP3 field descriptions

Field	Description
31–9 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
CLP3	Calibration Value
	Calibration Value

35.3.15 ADC Plus-Side General Calibration Value Register (ADCx_CLP2)

For more information, see CLPD register description.

Address: Base address + 44h offset



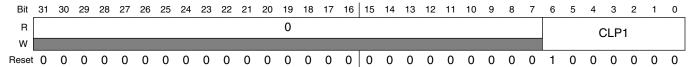
ADCx_CLP2 field descriptions

Field	Description
31–8 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.
CLP2	Calibration Value
	Calibration Value

35.3.16 ADC Plus-Side General Calibration Value Register (ADCx_CLP1)

For more information, see CLPD register description.

Address: Base address + 48h offset



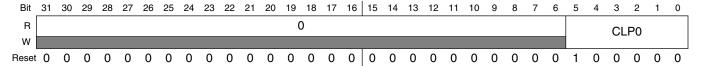
ADCx_CLP1 field descriptions

Field	Description			
31–7 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.			
CLP1	Calibration Value			
	Calibration Value			

35.3.17 ADC Plus-Side General Calibration Value Register (ADCx_CLP0)

For more information, see CLPD register description.

Address: Base address + 4Ch offset



ADCx_CLP0 field descriptions

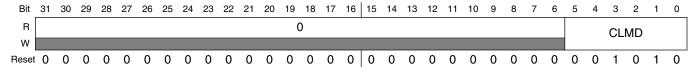
Field	Description				
31–6 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.				
	Calibration Value				
	Calibration Value				

35.3.18 ADC Minus-Side General Calibration Value Register (ADCx_CLMD)

The Minus-Side General Calibration Value (CLMx) registers contain calibration information that is generated by the calibration function. These registers contain seven calibration values of varying widths: CLM0[5:0], CLM1[6:0], CLM2[7:0], CLM3[8:0], CLM4[9:0], CLMS[5:0], and CLMD[5:0]. CLMx are automatically set when the self-calibration sequence is done, that is, CAL is cleared. If these registers are written by the user after calibration, the linearity error specifications may not be met.

For more information regarding the calibration procedure, please refer to the Calibration function section.





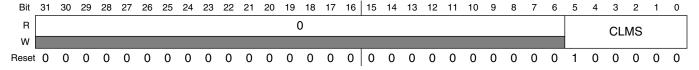
ADCx_CLMD field descriptions

Field	Description			
31–6 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.			
	Calibration Value			
	Calibration Value			

35.3.19 ADC Minus-Side General Calibration Value Register (ADCx_CLMS)

For more information, see CLMD register description.

Address: Base address + 58h offset



ADCx_CLMS field descriptions

Field	Description				
31–6 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.				

Table continues on the next page...

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Memory map and register definitions

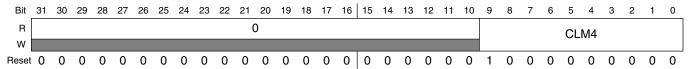
ADCx_CLMS field descriptions (continued)

Field	Description
CLMS	Calibration Value
	Calibration Value

35.3.20 ADC Minus-Side General Calibration Value Register (ADCx_CLM4)

For more information, see CLMD register description.





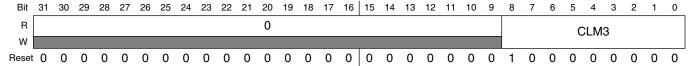
ADCx_CLM4 field descriptions

Field	Description			
31–10 Reserved	This field is reserved.			
Reserved	This read-only field is reserved and always has the value 0.			
CLM4	Calibration Value			
	Calibration Value			

35.3.21 ADC Minus-Side General Calibration Value Register (ADCx_CLM3)

For more information, see CLMD register description.

Address: Base address + 60h offset



ADCx CLM3 field descriptions

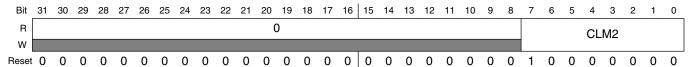
Field	Description			
31–9	nis field is reserved.			
Reserved	This read-only field is reserved and always has the value 0.			
CLM3	Calibration Value			
	Calibration Value			

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35.3.22 ADC Minus-Side General Calibration Value Register (ADCx_CLM2)

For more information, see CLMD register description.

Address: Base address + 64h offset



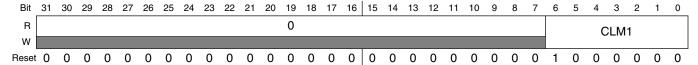
ADCx CLM2 field descriptions

Field	Description			
31–8 Reserved	This field is reserved.			
Reserved	This read-only field is reserved and always has the value 0.			
CLM2	Calibration Value			
	Calibration Value			

35.3.23 ADC Minus-Side General Calibration Value Register (ADCx_CLM1)

For more information, see CLMD register description.

Address: Base address + 68h offset



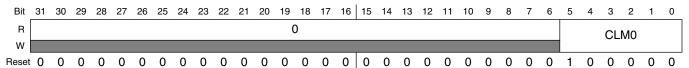
ADCx_CLM1 field descriptions

Field	Description			
31–7 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.			
CLM1	Calibration Value			
	Calibration Value			

35.3.24 ADC Minus-Side General Calibration Value Register (ADCx_CLM0)

For more information, see CLMD register description.





ADCx CLM0 field descriptions

Field	Description			
31–6 Reserved	This field is reserved. This read-only field is reserved and always has the value 0.			
CLM0	Calibration Value			
	Calibration Value			

35.4 Functional description

The ADC module is disabled during reset, in Low-Power Stop mode, or when SC1n[ADCH] are all high; see the power management information for details. The module is idle when a conversion has completed and another conversion has not been initiated. When it is idle and the asynchronous clock output enable is disabled, or CFG2[ADACKEN]= 0, the module is in its lowest power state. The ADC can perform an analog-to-digital conversion on any of the software selectable channels. All modes perform conversion by a successive approximation algorithm.

To meet accuracy specifications, the ADC module must be calibrated using the on-chip calibration function.

See Calibration function for details on how to perform calibration.

When the conversion is completed, the result is placed in the Rn data registers. The respective SC1n[COCO] is then set and an interrupt is generated if the respective conversion complete interrupt has been enabled, or, when SC1n[AIEN]=1.

The ADC module has the capability of automatically comparing the result of a conversion with the contents of the CV1 and CV2 registers. The compare function is enabled by setting SC2[ACFE] and operates in any of the conversion modes and configurations.

The ADC module has the capability of automatically averaging the result of multiple conversions. The hardware average function is enabled by setting SC3[AVGE] and operates in any of the conversion modes and configurations.

NOTE

For the chip specific modes of operation, see the power management information of this MCU.

35.4.1 Clock select and divide control

One of four clock sources can be selected as the clock source for the ADC module.

This clock source is then divided by a configurable value to generate the input clock ADCK, to the module. The clock is selected from one of the following sources by means of CFG1[ADICLK].

- Bus clock. This is the default selection following reset.
- Bus clock divided by two. For higher bus clock rates, this allows a maximum divideby-16 of the bus clock using CFG1[ADIV].
- ALTCLK: As defined for this MCU. See the chip configuration information. Conversions are possible using ALTCLK as the input clock source while the MCU is in Normal Stop mode.
- Asynchronous clock (ADACK): This clock is generated from a clock source within the ADC module. When the ADACK clock source is selected, it is not required to be active prior to conversion start. When it is selected and it is not active prior to a conversion start CFG2[ADACKEN]=0, ADACK is activated at the start of a conversion and deactivated when conversions are terminated. In this case, there is an associated clock startup delay each time the clock source is re-activated. To avoid the conversion time variability and latency associated with the ADACK clock startup, set CFG2[ADACKEN]=1 and wait the worst-case startup time of 5 µs prior to initiating any conversions using the ADACK clock source. Conversions are possible using ADACK as the input clock source while the MCU is in Normal Stop mode. See Power Control for more information.

Whichever clock is selected, its frequency must fall within the specified frequency range for ADCK. If the available clocks are too slow, the ADC may not perform according to specifications. If the available clocks are too fast, the clock must be divided to the appropriate frequency. This divider is specified by CFG1[ADIV] and can be divide-by 1, 2, 4, or 8.

35.4.2 Voltage reference selection

The ADC can be configured to accept one of the two voltage reference pairs as the reference voltage (V_{REFSH} and V_{REFSL}) used for conversions.

Each pair contains a positive reference that must be between the minimum Ref Voltage High and V_{DDA} , and a ground reference that must be at the same potential as V_{SSA} . The two pairs are external (V_{REFH} and V_{REFL}) and alternate (V_{ALTH} and V_{ALTL}). These voltage references are selected using SC2[REFSEL]. The alternate (V_{ALTH} and V_{ALTL}) voltage reference pair may select additional external pins or internal sources depending on MCU configuration. See the chip configuration information on the voltage references specific to this MCU.

35.4.3 Hardware trigger and channel selects

The ADC module has a selectable asynchronous hardware conversion trigger, ADHWT, that is enabled when SC2[ADTRG] is set and a hardware trigger select event, ADHWTSn, has occurred.

This source is not available on all MCUs. See the chip-specific ADC information for information on the ADHWT source and the ADHWTSn configurations specific to this MCU.

When an ADHWT source is available and hardware trigger is enabled, that is SC2[ADTRG]=1, a conversion is initiated on the rising-edge of ADHWT after a hardware trigger select event, that is, ADHWTSn, has occurred. If a conversion is in progress when a rising-edge of a trigger occurs, the rising-edge is ignored. In continuous convert configuration, only the initial rising-edge to launch continuous conversions is observed, and until conversion is aborted, the ADC continues to do conversions on the same SCn register that initiated the conversion. The hardware trigger function operates in conjunction with any of the conversion modes and configurations.

The hardware trigger select event, ADHWTSn, must be set prior to the receipt of the ADHWT signal. If these conditions are not met, the converter may ignore the trigger or use the incorrect configuration. If a hardware trigger select event is asserted during a conversion, it must stay asserted until the end of current conversion and remain set until the receipt of the ADHWT signal to trigger a new conversion. The channel and status fields selected for the conversion depend on the active trigger select signal:

- ADHWTSA active selects SC1A.
- ADHWTSn active selects SC1n.

Note

Asserting more than one hardware trigger select signal (ADHWTSn) at the same time results in unknown results. To avoid this, select only one hardware trigger select signal (ADHWTSn) prior to the next intended conversion.

When the conversion is completed, the result is placed in the Rn registers associated with the ADHWTSn received. For example:

- ADHWTSA active selects RA register
- ADHWTSn active selects Rn register

The conversion complete flag associated with the ADHWTSn received, that is, SC1n[COCO], is then set and an interrupt is generated if the respective conversion complete interrupt has been enabled, that is, SC1[AIEN]=1.

35.4.4 Conversion control

Conversions can be performed as determined by CFG1[MODE] and SC1n[DIFF] as shown in the description of CFG1[MODE].

Conversions can be initiated by a software or hardware trigger.

In addition, the ADC module can be configured for:

- Low-power operation
- Long sample time
- Continuous conversion
- Hardware average
- Automatic compare of the conversion result to a software determined compare value

35.4.4.1 Initiating conversions

A conversion is initiated:

- Following a write to SC1A, with SC1n[ADCH] not all 1's, if software triggered operation is selected, that is, when SC2[ADTRG]=0.
- Following a hardware trigger, or ADHWT event, if hardware triggered operation is selected, that is, SC2[ADTRG]=1, and a hardware trigger select event, ADHWTSn, has occurred. The channel and status fields selected depend on the active trigger select signal:
 - ADHWTSA active selects SC1A.

Functional description

- ADHWTSn active selects SC1n.
- if neither is active, the off condition is selected

Note

Selecting more than one ADHWTSn prior to a conversion completion will result in unknown results. To avoid this, select only one ADHWTSn prior to a conversion completion.

• Following the transfer of the result to the data registers when continuous conversion is enabled, that is, when SC3[ADCO] = 1.

If continuous conversions are enabled, a new conversion is automatically initiated after the completion of the current conversion. In software triggered operation, that is, when SC2[ADTRG] = 0, continuous conversions begin after SC1A is written and continue until aborted. In hardware triggered operation, that is, when SC2[ADTRG] = 1 and one ADHWTSn event has occurred, continuous conversions begin after a hardware trigger event and continue until aborted.

If hardware averaging is enabled, a new conversion is automatically initiated after the completion of the current conversion until the correct number of conversions are completed. In software triggered operation, conversions begin after SC1A is written. In hardware triggered operation, conversions begin after a hardware trigger. If continuous conversions are also enabled, a new set of conversions to be averaged are initiated following the last of the selected number of conversions.

35.4.4.2 Completing conversions

A conversion is completed when the result of the conversion is transferred into the data result registers, Rn. If the compare functions are disabled, this is indicated by setting of SC1n[COCO]. If hardware averaging is enabled, the respective SC1n[COCO] sets only if the last of the selected number of conversions is completed. If the compare function is enabled, the respective SC1n[COCO] sets and conversion result data is transferred only if the compare condition is true. If both hardware averaging and compare functions are enabled, then the respective SC1n[COCO] sets only if the last of the selected number of conversions is completed and the compare condition is true. An interrupt is generated if the respective SC1n[AIEN] is high at the time that the respective SC1n[COCO] is set.

35.4.4.3 Aborting conversions

Any conversion in progress is aborted when:

- Writing to SC1A while it is actively controlling a conversion, aborts the current conversion. In Software Trigger mode, when SC2[ADTRG]=0, a write to SC1A initiates a new conversion if SC1A[ADCH] is equal to a value other than all 1s. Writing to any of the SC1B–SC1n registers while that specific SC1B–SC1n register is actively controlling a conversion aborts the current conversion. The SC1(B-n) registers are not used for software trigger operation and therefore writes to the SC1(B-n) registers do not initiate a new conversion.
- A write to any ADC register besides the SC1A-SC1n registers occurs. This indicates that a change in mode of operation has occurred and the current conversion is therefore invalid.
- The MCU is reset or enters Low-Power Stop modes.
- The MCU enters Normal Stop mode with ADACK or Alternate Clock Sources not enabled.

When a conversion is aborted, the contents of the data registers, Rn, are not altered. The data registers continue to be the values transferred after the completion of the last successful conversion. If the conversion was aborted by a reset or Low-Power Stop modes, RA and Rn return to their reset states.

35.4.4.4 Power control

The ADC module remains in its idle state until a conversion is initiated. If ADACK is selected as the conversion clock source, but the asynchronous clock output is disabled, that is CFG2[ADACKEN]=0, the ADACK clock generator also remains in its idle state (disabled) until a conversion is initiated. If the asynchronous clock output is enabled, that is, CFG2[ADACKEN]=1, it remains active regardless of the state of the ADC or the MCU power mode.

Power consumption when the ADC is active can be reduced by setting CFG1[ADLPC]. This results in a lower maximum value for f_{ADCK} .

35.4.4.5 Sample time and total conversion time

For short sample, that is, when CFG1[ADLSMP]=0, there is a 2-cycle adder for first conversion over the base sample time of four ADCK cycles. For high-speed conversions, that is, when CFG2[ADHSC]=1, there is an additional 2-cycle adder on any conversion. The table below summarizes sample times for the possible ADC configurations.

ADC configuration			Sample time (ADCK cycles)	
CFG1[ADLSMP]	CFG2[ADLSTS]	CFG2[ADHSC]	First or Single Subsequent	
0	X	0	6	4
1	00	0	24	
1	01	0	16	
1	10	0	10	
1	11	0	6	
0	X	1	8	6
1	00	1	26	
1	01	1	18	
1	10	1	12	
1	11	1	8	

The total conversion time depends upon:

- The sample time as determined by CFG1[ADLSMP] and CFG2[ADLSTS]
- The MCU bus frequency
- The conversion mode, as determined by CFG1[MODE] and SC1n[DIFF]
- The high-speed configuration, that is, CFG2[ADHSC]
- The frequency of the conversion clock, that is, f_{ADCK}.

CFG2[ADHSC] is used to configure a higher clock input frequency. This will allow faster overall conversion times. To meet internal ADC timing requirements, CFG2[ADHSC] adds additional ADCK cycles. Conversions with CFG2[ADHSC]=1 take two more ADCK cycles. CFG2[ADHSC] must be used when the ADCLK exceeds the limit for CFG2[ADHSC]=0.

After the module becomes active, sampling of the input begins.

- 1. CFG1[ADLSMP] and CFG2[ADLSTS] select between sample times based on the conversion mode that is selected.
- 2. When sampling is completed, the converter is isolated from the input channel and a successive approximation algorithm is applied to determine the digital value of the analog signal.
- 3. The result of the conversion is transferred to Rn upon completion of the conversion algorithm.

If the bus frequency is less than f_{ADCK} , precise sample time for continuous conversions cannot be guaranteed when short sample is enabled, that is, when CFG1[ADLSMP]=0.

The maximum total conversion time is determined by the clock source chosen and the divide ratio selected. The clock source is selectable by CFG1[ADICLK], and the divide ratio is specified by CFG1[ADIV].

The maximum total conversion time for all configurations is summarized in the equation below. See the following tables for the variables referenced in the equation.

ConversionTime = SFCAdder + AverageNum × (BCT + LSTAdder + HSCAdder)

Equation 1. Conversion time equation

Table 35-3. Single or first continuous time adder (SFCAdder)

CFG1[AD LSMP]	CFG2[AD ACKEN]	CFG1[ADICLK]	Single or first continuous time adder (SFCAdder)
1	х	0x, 10	3 ADCK cycles + 5 bus clock cycles
1	1	11	3 ADCK cycles + 5 bus clock cycles ¹
1	0	11	5 μs + 3 ADCK cycles + 5 bus clock cycles
0	х	0x, 10	5 ADCK cycles + 5 bus clock cycles
0	1	11	5 ADCK cycles + 5 bus clock cycles ¹
0	0	11	5 μs + 5 ADCK cycles + 5 bus clock cycles

1. To achieve this time, CFG2[ADACKEN] must be 1 for at least 5 µs prior to the conversion is initiated.

Table 35-4. Average number factor (AverageNum)

SC3[AVGE]	SC3[AVGS]	Average number factor (AverageNum)
0	XX	1
1	00	4
1	01	8
1	10	16
1	11	32

Table 35-5. Base conversion time (BCT)

Mode	Base conversion time (BCT)
8b single-ended	17 ADCK cycles
9b differential	27 ADCK cycles
10b single-ended	20 ADCK cycles
11b differential	30 ADCK cycles
12b single-ended	20 ADCK cycles
13b differential	30 ADCK cycles

Table continues on the next page...

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Table 35-5. Base conversion time (BCT) (continued)

Mode	Base conversion time (BCT)
16b single-ended	25 ADCK cycles
16b differential	34 ADCK cycles

Table 35-6. Long sample time adder (LSTAdder)

CFG1[ADLSMP]	CFG2[ADLSTS]	Long sample time adder (LSTAdder)
0	xx	0 ADCK cycles
1	00	20 ADCK cycles
1	01	12 ADCK cycles
1	10	6 ADCK cycles
1	11	2 ADCK cycles

Table 35-7. High-speed conversion time adder (HSCAdder)

CFG2[ADHSC]	High-speed conversion time adder (HSCAdder)
0	0 ADCK cycles
1	2 ADCK cycles

Note

The ADCK frequency must be between f_{ADCK} minimum and f_{ADCK} maximum to meet ADC specifications.

35.4.4.6 Conversion time examples

The following examples use the Equation 1 on page 881, and the information provided in Table 35-3 through Table 35-7.

35.4.4.6.1 Typical conversion time configuration

A typical configuration for ADC conversion is:

- 10-bit mode, with the bus clock selected as the input clock source
- The input clock divide-by-1 ratio selected
- Bus frequency of 8 MHz
- Long sample time disabled
- High-speed conversion disabled

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The conversion time for a single conversion is calculated by using the Equation 1 on page 881, and the information provided in Table 35-3 through Table 35-7. The table below lists the variables of Equation 1 on page 881.

Table 35-8. Typical conversion time

Variable	Time
SFCAdder	5 ADCK cycles + 5 bus clock cycles
AverageNum	1
ВСТ	20 ADCK cycles
LSTAdder	0
HSCAdder	0

The resulting conversion time is generated using the parameters listed in the preceding table. Therefore, for a bus clock and an ADCK frequency equal to 8 MHz, the resulting conversion time is $3.75 \, \mu s$.

35.4.4.6.2 Long conversion time configuration

A configuration for long ADC conversion is:

- 16-bit differential mode with the bus clock selected as the input clock source
- The input clock divide-by-8 ratio selected
- Bus frequency of 8 MHz
- Long sample time enabled
- Configured for longest adder
- High-speed conversion disabled
- Average enabled for 32 conversions

The conversion time for this conversion is calculated by using the Equation 1 on page 881, and the information provided in Table 35-3 through Table 35-7. The following table lists the variables of the Equation 1 on page 881.

Table 35-9. Typical conversion time

Variable	Time
SFCAdder	3 ADCK cycles + 5 bus clock cycles
AverageNum	32
ВСТ	34 ADCK cycles
LSTAdder	20 ADCK cycles
HSCAdder	0

The resulting conversion time is generated using the parameters listed in the preceding table. Therefore, for bus clock equal to 8 MHz and ADCK equal to 1 MHz, the resulting conversion time is $57.625~\mu s$, that is, AverageNum. This results in a total conversion time of 1.844~m s.

35.4.4.6.3 Short conversion time configuration

A configuration for short ADC conversion is:

- 8-bit Single-Ended mode with the bus clock selected as the input clock source
- The input clock divide-by-1 ratio selected
- Bus frequency of 20 MHz
- Long sample time disabled
- High-speed conversion enabled

The conversion time for this conversion is calculated by using the Equation 1 on page 881, and the information provided in Table 35-3 through Table 35-7. The table below lists the variables of Equation 1 on page 881.

Variable	Time
SFCAdder	5 ADCK cycles + 5 bus clock cycles
AverageNum	1
ВСТ	17 ADCK cycles
LSTAdder	0 ADCK cycles
HSCAdder	2

Table 35-10. Typical conversion time

The resulting conversion time is generated using the parameters listed in in the preceding table. Therefore, for bus clock and ADCK frequency equal to 20 MHz, the resulting conversion time is 1.45 µs.

35.4.4.7 Hardware average function

The hardware average function can be enabled by setting SC3[AVGE]=1 to perform a hardware average of multiple conversions. The number of conversions is determined by the AVGS[1:0] bits, which can select 4, 8, 16, or 32 conversions to be averaged. While the hardware average function is in progress, SC2[ADACT] will be set.

After the selected input is sampled and converted, the result is placed in an accumulator from which an average is calculated once the selected number of conversions have been completed. When hardware averaging is selected, the completion of a single conversion will not set SC1n[COCO].

If the compare function is either disabled or evaluates true, after the selected number of conversions are completed, the average conversion result is transferred into the data result registers, Rn, and SC1n[COCO] is set. An ADC interrupt is generated upon the setting of SC1n[COCO] if the respective ADC interrupt is enabled, that is, SC1n[AIEN]=1.

Note

The hardware average function can perform conversions on a channel while the MCU is in Wait or Normal Stop modes. The ADC interrupt wakes the MCU when the hardware average is completed if SC1n[AIEN] is set.

35.4.5 Automatic compare function

The compare function can be configured to check whether the result is less than or greater-than-or-equal-to a single compare value, or, if the result falls within or outside a range determined by two compare values.

The compare mode is determined by SC2[ACFGT], SC2[ACREN], and the values in the compare value registers, CV1 and CV2. After the input is sampled and converted, the compare values in CV1 and CV2 are used as described in the following table. There are six Compare modes as shown in the following table.

ADCCV1 SC2[AC SC2[AC **Function** relative to Compare mode description REN] FGT] ADCCV2 0 0 Less than threshold Compare true if the result is less than the CV1 registers. 1 0 Greater than or equal to threshold Compare true if the result is greater than or equal to CV1 registers. 0 1 Compare true if the result is less than CV1 Less than or Outside range, not inclusive Or the result is greater than CV2. egual 1 0 Greater than Compare true if the result is less than CV1 Inside range, not inclusive And the result is greater than CV2. 1 Less than or Inside range, inclusive Compare true if the result is greater than or egual equal to CV1 **And** the result is less than or equal to CV2. 1 1 Greater than Outside range, inclusive Compare true if the result is greater than or equal to CV1 Or the result is less than or equal to CV2.

Table 35-11. Compare modes

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With SC2[ACREN] =1, and if the value of CV1 is less than or equal to the value of CV2, then setting SC2[ACFGT] will select a trigger-if-inside-compare-range inclusive-ofendpoints function. Clearing SC2[ACFGT] will select a trigger-if-outside-comparerange, not-inclusive-of-endpoints function.

If CV1 is greater than CV2, setting SC2[ACFGT] will select a trigger-if-outsidecompare-range, inclusive-of-endpoints function. Clearing SC2[ACFGT] will select a trigger-if-inside-compare-range, not-inclusive-of-endpoints function.

If the condition selected evaluates true, SC1n[COCO] is set.

Upon completion of a conversion while the compare function is enabled, if the compare condition is not true, SC1n[COCO] is not set and the conversion result data will not be transferred to the result register, Rn. If the hardware averaging function is enabled, the compare function compares the averaged result to the compare values. The same compare function definitions apply. An ADC interrupt is generated when SC1n[COCO] is set and the respective ADC interrupt is enabled, that is, SC1n[AIEN]=1.

Note

The compare function can monitor the voltage on a channel while the MCU is in Wait or Normal Stop modes. The ADC interrupt wakes the MCU when the compare condition is met.

35.4.6 Calibration function

The ADC contains a self-calibration function that is required to achieve the specified accuracy.

Calibration must be run, or valid calibration values written, after any reset and before a conversion is initiated. The calibration function sets the offset calibration value, the minus-side calibration values, and the plus-side calibration values. The offset calibration value is automatically stored in the ADC offset correction register (OFS), and the plusside and minus-side calibration values are automatically stored in the ADC plus-side and minus-side calibration registers, CLPx and CLMx. The user must configure the ADC correctly prior to calibration, and must generate the plus-side and minus-side gain calibration results and store them in the ADC plus-side gain register (PG) after the calibration function completes.

Prior to calibration, the user must configure the ADC's clock source and frequency, low power configuration, voltage reference selection, sample time, and high speed configuration according to the application's clock source availability and needs. If the

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application uses the ADC in a wide variety of configurations, the configuration for which the highest accuracy is required should be selected, or multiple calibrations can be done for the different configurations. For best calibration results:

- Set hardware averaging to maximum, that is, SC3[AVGE]=1 and SC3[AVGS]=11 for an average of 32
- Set ADC clock frequency f_{ADCK} less than or equal to 4 MHz
- V_{REFH}=V_{DDA}
- Calibrate at nominal voltage and temperature

The input channel, conversion mode continuous function, compare function, resolution mode, and differential/single-ended mode are all ignored during the calibration function.

To initiate calibration, the user sets SC3[CAL] and the calibration will automatically begin if the SC2[ADTRG] is 0. If SC2[ADTRG] is 1, SC3[CAL] will not get set and SC3[CALF] will be set. While calibration is active, no ADC register can be written and no stop mode may be entered, or the calibration routine will be aborted causing SC3[CAL] to clear and SC3[CALF] to set. At the end of a calibration sequence, SC1n[COCO] will be set. SC1n[AIEN] can be used to allow an interrupt to occur at the end of a calibration sequence. At the end of the calibration routine, if SC3[CALF] is not set, the automatic calibration routine is completed successfully.

To complete calibration, the user must generate the gain calibration values using the following procedure:

- 1. Initialize or clear a 16-bit variable in RAM.
- 2. Add the plus-side calibration results CLP0, CLP1, CLP2, CLP3, CLP4, and CLPS to the variable.
- 3. Divide the variable by two.
- 4. Set the MSB of the variable.
- 5. The previous two steps can be achieved by setting the carry bit, rotating to the right through the carry bit on the high byte and again on the low byte.
- 6. Store the value in the plus-side gain calibration register PG.
- 7. Repeat the procedure for the minus-side gain calibration value.

When calibration is complete, the user may reconfigure and use the ADC as desired. A second calibration may also be performed, if desired, by clearing and again setting SC3[CAL].

Overall, the calibration routine may take as many as 14k ADCK cycles and 100 bus cycles, depending on the results and the clock source chosen. For an 8 MHz clock source, this length amounts to about 1.7 ms. To reduce this latency, the calibration values, which are offset, plus-side and minus-side gain, and plus-side and minus-side calibration values, may be stored in flash memory after an initial calibration and recovered prior to the first ADC conversion. This method can reduce the calibration latency to 20 register store operations on all subsequent power, reset, or Low-Power Stop mode recoveries.

Further information on the calibration procedure can be found in the Calibration section of AN3949: ADC16 Calibration Procedure and Programmable Delay Block Synchronization.

35.4.7 User-defined offset function

OFS contains the user-selected or calibration-generated offset error correction value.

This register is a 2's complement, left-justified. The value in OFS is subtracted from the conversion and the result is transferred into the result registers, Rn. If the result is greater than the maximum or less than the minimum result value, it is forced to the appropriate limit for the current mode of operation.

The formatting of the OFS is different from the data result register, Rn, to preserve the resolution of the calibration value regardless of the conversion mode selected. Lower order bits are ignored in lower resolution modes. For example, in 8-bit single-ended mode, OFS[14:7] are subtracted from D[7:0]; OFS[15] indicates the sign (negative numbers are effectively added to the result) and OFS[6:0] are ignored. The same bits are used in 9-bit differential mode because OFS[15] indicates the sign bit, which maps to D[8]. For 16-bit differential mode, OFS[15:0] are directly subtracted from the conversion result data D[15:0]. In 16-bit single-ended mode, there is no field in the OFS corresponding to the least significant result D[0], so odd values, such as -1 or +1, cannot be subtracted from the result.

OFS is automatically set according to calibration requirements once the self-calibration sequence is done, that is, SC3[CAL] is cleared. The user may write to OFS to override the calibration result if desired. If the OFS is written by the user to a value that is different from the calibration value, the ADC error specifications may not be met. Storing the value generated by the calibration function in memory before overwriting with a user-specified value is recommended.

Note

There is an effective limit to the values of offset that can be set by the user. If the magnitude of the offset is too high, the results of the conversions will cap off at the limits.

The offset calibration function may be employed by the user to remove application offsets or DC bias values. OFS may be written with a number in 2's complement format and this offset will be subtracted from the result, or hardware averaged value. To add an offset, store the negative offset in 2's complement format and the effect will be an addition. An offset correction that results in an out-of-range value will be forced to the minimum or maximum value. The minimum value for single-ended conversions is 0x0000; for a differential conversion it is 0x8000.

To preserve accuracy, the calibrated offset value initially stored in OFS must be added to the user-defined offset. For applications that may change the offset repeatedly during operation, store the initial offset calibration value in flash so it can be recovered and added to any user offset adjustment value and the sum stored in OFS.

35.4.8 Temperature sensor

The ADC module includes a temperature sensor whose output is connected to one of the ADC analog channel inputs.

The following equation provides an approximate transfer function of the temperature sensor.

$$Temp = 25 - ((V_{TEMP} - V_{TEMP25}) \div m)$$

Equation 2. Approximate transfer function of the temperature sensor

where:

- \bullet V_{TEMP} is the voltage of the temperature sensor channel at the ambient temperature.
- V_{TEMP25} is the voltage of the temperature sensor channel at 25 °C.
- m is referred as temperature sensor slope in the device data sheet. It is the hot or cold voltage versus temperature slope in V/°C.

For temperature calculations, use the V_{TEMP25} and temperature sensor slope values from the ADC Electricals table.

In application code, the user reads the temperature sensor channel, calculates V_{TEMP} , and compares to V_{TEMP25} . If V_{TEMP} is greater than V_{TEMP25} the cold slope value is applied in the preceding equation. If V_{TEMP} is less than V_{TEMP25} , the hot slope value is applied in the preceding equation. ADC Electricals table may only specify one temperature sensor slope value. In that case, the user could use the same slope for the calculation across the operational temperature range.

For more information on using the temperature sensor, see the application note titled *Temperature Sensor for the HCS08 Microcontroller Family* (document AN3031).

35.4.9 MCU wait mode operation

Wait mode is a lower-power consumption Standby mode from which recovery is fast because the clock sources remain active.

If a conversion is in progress when the MCU enters Wait mode, it continues until completion. Conversions can be initiated while the MCU is in Wait mode by means of the hardware trigger or if continuous conversions are enabled.

The bus clock, bus clock divided by two; and ADACK are available as conversion clock sources while in Wait mode. The use of ALTCLK as the conversion clock source in Wait is dependent on the definition of ALTCLK for this MCU. See the Chip Configuration information on ALTCLK specific to this MCU.

If the compare and hardware averaging functions are disabled, a conversion complete event sets SC1n[COCO] and generates an ADC interrupt to wake the MCU from Wait mode if the respective ADC interrupt is enabled, that is, when SC1n[AIEN]=1. If the hardware averaging function is enabled, SC1n[COCO] will set, and generate an interrupt if enabled, when the selected number of conversions are completed. If the compare function is enabled, SC1n[COCO] will set, and generate an interrupt if enabled, only if the compare conditions are met. If a single conversion is selected and the compare trigger is not met, the ADC will return to its idle state and cannot wake the MCU from Wait mode unless a new conversion is initiated by the hardware trigger.

35.4.10 MCU Normal Stop mode operation

Stop mode is a low-power consumption Standby mode during which most or all clock sources on the MCU are disabled.

35.4.10.1 Normal Stop mode with ADACK disabled

If the asynchronous clock, ADACK, is not selected as the conversion clock, executing a stop instruction aborts the current conversion and places the ADC in its Idle state. The contents of the ADC registers, including Rn, are unaffected by Normal Stop mode. After exiting from Normal Stop mode, a software or hardware trigger is required to resume conversions.

35.4.10.2 Normal Stop mode with ADACK enabled

If ADACK is selected as the conversion clock, the ADC continues operation during Normal Stop mode. See the chip-specific ADC information for configuration information for this device.

If a conversion is in progress when the MCU enters Normal Stop mode, it continues until completion. Conversions can be initiated while the MCU is in Normal Stop mode by means of the hardware trigger or if continuous conversions are enabled.

If the compare and hardware averaging functions are disabled, a conversion complete event sets SC1n[COCO] and generates an ADC interrupt to wake the MCU from Normal Stop mode if the respective ADC interrupt is enabled, that is, when SC1n[AIEN]=1. The result register, Rn, will contain the data from the first completed conversion that occurred during Normal Stop mode. If the hardware averaging function is enabled, SC1n[COCO] will set, and generate an interrupt if enabled, when the selected number of conversions are completed. If the compare function is enabled, SC1n[COCO] will set, and generate an interrupt if enabled, only if the compare conditions are met. If a single conversion is selected and the compare is not true, the ADC will return to its idle state and cannot wake the MCU from Normal Stop mode unless a new conversion is initiated by another hardware trigger.

35.4.11 MCU Low-Power Stop mode operation

The ADC module is automatically disabled when the MCU enters Low-Power Stop mode.

All module registers contain their reset values following exit from Low-Power Stop mode. Therefore, the module must be re-enabled and re-configured following exit from Low-Power Stop mode.

NOTE

For the chip specific modes of operation, see the power management information for the device.

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35.5 Initialization information

This section gives an example that provides some basic direction on how to initialize and configure the ADC module.

The user can configure the module for 16-bit, 12-bit, 10-bit, or 8-bit single-ended resolution or 16-bit, 13-bit, 11-bit, or 9-bit differential resolution, single or continuous conversion, and a polled or interrupt approach, among many other options. For information used in this example, refer to Table 35-6, Table 35-7, and Table 35-8.

Note

Hexadecimal values are designated by a preceding 0x, binary values designated by a preceding %, and decimal values have no preceding character.

35.5.1 ADC module initialization example

35.5.1.1 Initialization sequence

Before the ADC module can be used to complete conversions, an initialization procedure must be performed. A typical sequence is:

- 1. Calibrate the ADC by following the calibration instructions in Calibration function.
- 2. Update CFG to select the input clock source and the divide ratio used to generate ADCK. This register is also used for selecting sample time and low-power configuration.
- 3. Update SC2 to select the conversion trigger, hardware or software, and compare function options, if enabled.
- 4. Update SC3 to select whether conversions will be continuous or completed only once (ADCO) and whether to perform hardware averaging.
- 5. Update SC1:SC1n registers to select whether conversions will be single-ended or differential and to enable or disable conversion complete interrupts. Also, select the input channel which can be used to perform conversions.

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35.5.1.2 Pseudo-code example

In this example, the ADC module is set up with interrupts enabled to perform a single 10-bit conversion at low-power with a long sample time on input channel 1, where ADCK is derived from the bus clock divided by 1.

CFG1 = 0x98 (% 10011000)

```
Bit 7 ADLPC 1 Configures for low power, lowers maximum clock speed.

Bit 6:5 ADIV 00 Sets the ADCK to the input clock ÷ 1.

Bit 4 ADLSMP 1 Configures for long sample time.

Bit 3:2 MODE 10 Selects the single-ended 10-bit conversion, differential 11-bit conversion.

Bit 1:0 ADICLK 00 Selects the bus clock.
```

SC2 = 0x00 (%00000000)

```
Bit 7
                                   Flag indicates if a conversion is in progress.
                 ADACT
                          0
        Bit 6
                ADTRG
                        0
                                   Software trigger selected.
                                   Compare function disabled.
        Bit 5
                ACFE
        Bit 4
               ACFGT
                        0
                                  Not used in this example.
               ACREN 0
                                 Compare range disabled.
        Bit 3
Bit 2 DMAEN 0 DMA request disabled.
        Bit 1:0 REFSEL 00
                                 Selects default voltage reference pin pair (External pins
\textbf{V}_{\text{REFH}} and \textbf{V}_{\text{REFL}}) .
```

SC1A = 0x41 (%01000001)

```
Bit 7 COCO 0 Read-only flag which is set when a conversion completes.
Bit 6 AIEN 1 Conversion complete interrupt enabled.
Bit 5 DIFF 0 Single-ended conversion selected.
Bit 4:0 ADCH 00001 Input channel 1 selected as ADC input channel.
```

RA = 0xxx

Holds results of conversion.

CV = 0xxx

Holds compare value when compare function enabled.

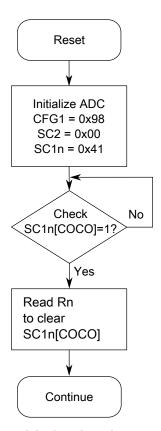


Figure 35-2. Initialization flowchart example

35.6 Application information

The ADC has been designed to be integrated into a microcontroller for use in embedded control applications requiring an ADC.

For guidance on selecting optimum external component values and converter parameters see AN4373: Cookbook for SAR ADC Measurements.

35.6.1 **External pins and routing**

Analog supply pins 35.6.1.1

Depending on the device, the analog power and ground supplies, V_{DDA} and V_{SSA} , of the ADC module are available as:

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- V_{DDA} and V_{SSA} available as separate pins—When available on a separate pin, both V_{DDA} and V_{SSA} must be connected to the same voltage potential as their corresponding MCU digital supply, V_{DD} and V_{SS}, and must be routed carefully for maximum noise immunity and bypass capacitors placed as near as possible to the package.
- V_{SSA} is shared on the same pin as the MCU digital V_{SS}.
- V_{SSA} and V_{DDA} are shared with the MCU digital supply pins—In these cases, there are separate pads for the analog supplies bonded to the same pin as the corresponding digital supply so that some degree of isolation between the supplies is maintained.

If separate power supplies are used for analog and digital power, the ground connection between these supplies must be at the V_{SSA} pin. This must be the only ground connection between these supplies, if possible. V_{SSA} makes a good single point ground location.

35.6.1.2 Analog voltage reference pins

In addition to the analog supplies, the ADC module has connections for two reference voltage inputs used by the converter:

- V_{REFSH} is the high reference voltage for the converter.
- V_{REFSL} is the low reference voltage for the converter.

The ADC can be configured to accept one of two voltage reference pairs for V_{REFSH} and V_{REFSL} . Each pair contains a positive reference and a ground reference. The two pairs are external, V_{REFH} and V_{REFL} and alternate, V_{ALTH} and V_{ALTL} . These voltage references are selected using SC2[REFSEL]. The alternate voltage reference pair, V_{ALTH} and V_{ALTL} , may select additional external pins or internal sources based on MCU configuration. See the chip configuration information on the voltage references specific to this MCU.

In some packages, the external or alternate pairs are connected in the package to V_{DDA} and V_{SSA} , respectively. One of these positive references may be shared on the same pin as V_{DDA} on some devices. One of these ground references may be shared on the same pin as V_{SSA} on some devices.

If externally available, the positive reference may be connected to the same potential as V_{DDA} or may be driven by an external source to a level between the minimum Ref Voltage High and the V_{DDA} potential. The positive reference must never exceed V_{DDA} . If externally available, the ground reference must be connected to the same voltage potential as V_{SSA} . The voltage reference pairs must be routed carefully for maximum noise immunity and bypass capacitors placed as near as possible to the package.

AC current in the form of current spikes required to supply charge to the capacitor array at each successive approximation step is drawn through the V_{REFH} and V_{REFL} loop. The best external component to meet this current demand is a 0.1 μF capacitor with good

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high-frequency characteristics. This capacitor is connected between V_{REFH} and V_{REFL} and must be placed as near as possible to the package pins. Resistance in the path is not recommended because the current causes a voltage drop that could result in conversion errors. Inductance in this path must be minimum, that is, parasitic only.

35.6.1.3 Analog input pins

The external analog inputs are typically shared with digital I/O pins on MCU devices.

Empirical data shows that capacitors on the analog inputs improve performance in the presence of noise or when the source impedance is high. Use of 0.01 μ F capacitors with good high-frequency characteristics is sufficient. These capacitors are not necessary in all cases, but when used, they must be placed as near as possible to the package pins and be referenced to V_{SSA} .

For proper conversion, the input voltage must fall between V_{REFH} and V_{REFL} . If the input is equal to or exceeds V_{REFH} , the converter circuit converts the signal to 0xFFF, which is full scale 12-bit representation, 0x3FF, which is full scale 10-bit representation, or 0xFF, which is full scale 8-bit representation. If the input is equal to or less than V_{REFL} , the converter circuit converts it to 0x000. Input voltages between V_{REFH} and V_{REFL} are straight-line linear conversions. There is a brief current associated with V_{REFL} when the sampling capacitor is charging.

For minimal loss of accuracy due to current injection, pins adjacent to the analog input pins must not be transitioning during conversions.

35.6.2 Sources of error

35.6.2.1 Sampling error

For proper conversions, the input must be sampled long enough to achieve the proper accuracy.

RAS + RADIN =SC / (FMAX * NUMTAU * CADIN)

Figure 35-3. Sampling equation

Where:

RAS = External analog source resistance

SC = Number of ADCK cycles used during sample window

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CADIN = Internal ADC input capacitance

 $NUMTAU = -ln(LSBERR / 2^{N})$

LSBERR = value of acceptable sampling error in LSBs

N = 8 in 8-bit mode, 10 in 10-bit mode, 12 in 12-bit mode or 16 in 16-bit mode

Higher source resistances or higher-accuracy sampling is possible by setting CFG1[ADLSMP] and changing CFG2[ADLSTS] to increase the sample window, or decreasing ADCK frequency to increase sample time.

35.6.2.2 Pin leakage error

Leakage on the I/O pins can cause conversion error if the external analog source resistance, R_{AS} , is high. If this error cannot be tolerated by the application, keep R_{AS} lower than V_{REFH} / (4 × I_{LEAK} × 2^N) for less than 1/4 LSB leakage error, where N=8 in 8-bit mode, 10 in 10-bit mode, 12 in 12-bit mode, or 16 in 16-bit mode.

35.6.2.3 Noise-induced errors

System noise that occurs during the sample or conversion process can affect the accuracy of the conversion. The ADC accuracy numbers are guaranteed as specified only if the following conditions are met:

- There is a 0.1 μF low-ESR capacitor from V_{REFH} to V_{REFL} .
- There is a 0.1 μF low-ESR capacitor from V_{DDA} to V_{SSA} .
- If inductive isolation is used from the primary supply, an additional 1 μF capacitor is placed from V_{DDA} to V_{SSA} .
- V_{SSA}, and V_{REFL}, if connected, is connected to V_{SS} at a quiet point in the ground plane.
- Operate the MCU in Wait or Normal Stop mode before initiating (hardware-triggered conversions) or immediately after initiating (hardware- or software-triggered conversions) the ADC conversion.

Application information

- For software triggered conversions, immediately follow the write to SC1 with a Wait instruction or Stop instruction.
- For Normal Stop mode operation, select ADACK as the clock source. Operation
 in Normal Stop reduces V_{DD} noise but increases effective conversion time due to
 stop recovery.
- There is no I/O switching, input or output, on the MCU during the conversion.

There are some situations where external system activity causes radiated or conducted noise emissions or excessive V_{DD} noise is coupled into the ADC. In these situations, or when the MCU cannot be placed in Wait or Normal Stop mode, or I/O activity cannot be halted, the following actions may reduce the effect of noise on the accuracy:

- Place a 0.01 μ F capacitor (C_{AS}) on the selected input channel to V_{REFL} or V_{SSA}. This improves noise issues, but affects the sample rate based on the external analog source resistance.
- Average the result by converting the analog input many times in succession and dividing the sum of the results. Four samples are required to eliminate the effect of a 1 LSB, one-time error.
- Reduce the effect of synchronous noise by operating off the asynchronous clock, that is, ADACK, and averaging. Noise that is synchronous to ADCK cannot be averaged out.

35.6.2.4 Code width and quantization error

The ADC quantizes the ideal straight-line transfer function into 65536 steps in the 16-bit mode. Each step ideally has the same height, that is, 1 code, and width. The width is defined as the delta between the transition points to one code and the next. The ideal code width for an N-bit converter, where N can be 16, 12, 10, or 8, defined as 1 LSB, is:

$$1LSB = (V_{REFH})/2^N$$

Equation 3. Ideal code width for an N-bit converter

There is an inherent quantization error due to the digitization of the result. For 8-bit, 10-bit, or 12-bit conversions, the code transitions when the voltage is at the midpoint between the points where the straight line transfer function is exactly represented by the actual transfer function. Therefore, the quantization error will be \pm 1/2 LSB in 8-bit, 10-bit, or 12-bit modes. As a consequence, however, the code width of the first (0x000) conversion is only 1/2 LSB and the code width of the last (0xFF or 0x3FF) is 1.5 LSB.

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For 16-bit conversions, the code transitions only after the full code width is present, so the quantization error is -1 LSB to 0 LSB and the code width of each step is 1 LSB.

35.6.2.5 Linearity errors

The ADC may also exhibit non-linearity of several forms. Every effort has been made to reduce these errors, but the system designers must be aware of these errors because they affect overall accuracy:

- Zero-scale error (E_{ZS}), sometimes called offset: This error is defined as the difference between the actual code width of the first conversion and the ideal code width. This is 1/2 LSB in 8-bit, 10-bit, or 12-bit modes and 1 LSB in 16-bit mode. If the first conversion is 0x001, the difference between the actual 0x001 code width and its ideal (1 LSB) is used.
- Full-scale error (E_{FS}): This error is defined as the difference between the actual code width of the last conversion and the ideal code width. This is 1.5 LSB in 8-bit, 10-bit, or 12-bit modes and 1 LSB in 16-bit mode. If the last conversion is 0x3FE, the difference between the actual 0x3FE code width and its ideal (1 LSB) is used.
- Differential non-linearity (DNL): This error is defined as the worst-case difference between the actual code width and the ideal code width for all conversions.
- Integral non-linearity (INL): This error is defined as the highest-value or absolute value that the running sum of DNL achieves. More simply, this is the worst-case difference of the actual transition voltage to a given code and its corresponding ideal transition voltage, for all codes.
- Total unadjusted error (TUE): This error is defined as the difference between the actual transfer function and the ideal straight-line transfer function and includes all forms of error.

35.6.2.6 Code jitter, non-monotonicity, and missing codes

Analog-to-digital converters are susceptible to three special forms of error:

• Code jitter: Code jitter occurs when a given input voltage converts to one of the two values when sampled repeatedly. Ideally, when the input voltage is infinitesimally smaller than the transition voltage, the converter yields the lower code, and viceversa. However, even small amounts of system noise can cause the converter to be indeterminate, between two codes, for a range of input voltages around the transition voltage.

Application information

This error may be reduced by repeatedly sampling the input and averaging the result. Additionally, the techniques discussed in Noise-induced errors reduces this error.

- Non-monotonicity: Non-monotonicity occurs when, except for code jitter, the converter converts to a lower code for a higher input voltage.
- Missing codes: Missing codes are those values never converted for any input value.

In 8-bit or 10-bit mode, the ADC is guaranteed to be monotonic and have no missing codes.